

Notice of References Cited	Application/Control No. 09/546,247	Applicant(s)/Patent Under Reexamination VAN LIEW ET AL.	
	Examiner David L Jones	Art Unit 2622	Page 1 of 1

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	B	US-5,539,539	07-1996	Fujimoto et al.	358/518
	C	US-5,257,119	10-1993	Funada et al.	358/438
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NON-PATENT DOCUMENTS

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